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Components, Hybrids, and Manufacturing Technology, IEEE Transactions on [see also IEEE Trans. on Component and Manufacturing Technology, Part A, B, C]  
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New Techniques in Providing Customer Services with Copper, IEE Colloquium on  
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Villeneuve, G.; Kulkarni, D.; Bastnagel, P.; Berry, D.;  
Electrical Contacts, 1996., Proceedings of the Forty-Second IEEE Holm Conference on ? Joint with the 18th Interna Conference on Electrical Contacts  
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Volume 6, Issue 1, Mar 1983 Page(s):21 - 27  
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Lin, C.M.; Grow, R.W.;  
Microwave Theory and Techniques, IEEE Transactions on  
Volume 6, Issue 4, Oct 1958 Page(s):454 - 454  
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8. Solderless high-density Interconnects for burn-In applications  
Guarin, F.J.; Katsetos, A.A.;  
Electronic Components and Technology Conference, 1992. Proceedings., 42nd  
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